

<b>Notice of References Cited</b>	Application/Control No. 09/918,886	Applicant(s)/Patent Under Reexamination YEE ET AL.	
	Examiner David S. Kim	Art Unit 2633	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,589,970	12-1996	Lyu et al.	398/95
*	B	US-2002/0076132 A1	06-2002	Peral et al.	385/15
*	C	US-6,735,395 B1	05-2004	Bai, Yu Sheng	398/95
*	D	US-6,766,116 B2	07-2004	Webb, Steven Michael	398/196
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.